



Sheet 1 of 1

Substitute	Form	PTO-	1449
(Modified)			

U.S. Department of Commerce Patent and Trademark Office Attorney's Docket No. 07977/252001

Application No. 09/198,073

Inf rmation DiscI sure Statement
by Applicant
(Use several sheets if necessary)

Applicant Shunpei Yamazaki, et al.

Filing Date

Group Art Unit

(37 CFR §1.98(b))

November 23, 1998 2871

U.S. Patent Documents							
Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	5,148,301	9/15/92	Sawatsubashi et al.			
	AB	5,261,156	11/16/93	Mase et al.			
	AC	5,654,811	8/5/97	Spitzer et al.			
	AD	5,757,456	5/26/98	Yamazaki et al.			
	AE	5,766,977	6/16/98	Yamazaki			
	AF	5,781,164	7/14/98	Jacobsen et al.		· · · · · · · · · · · · · · · · · · ·	
	AG	5,834,327	11/10/98	Yamazaki et al.			
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	Foreign	Patent Doc	uments or Pu	blished Foreign	Patent A	pplicatio	ns	
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	. Trans	lation No
	AL			: -				
	AM							
	AN							
	AO							
	AP							

	Other Documents (include Author, Title, Date, and Place of Publication)						
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	AQ						
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EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with					
next communication to applicant.					

Application/Control No. Applicant(s)/Patent Under Reexamination 09/198,073 YAMAZAKI ET AL. Notice of References Cited Examiner Art Unit Page 1 of MINH-TOAN T TON 2871 **U.S. PATENT DOCUMENTS Document Number** Date Country Code-Number-Kind Code Name Classification MM-YYYY US-5528403-06-1996 Α Kawaguchi et al 349 152 В US-US-D US-US-Ε F US-_ US-G US-Н US-US-J US-K US-М US-FOREIGN PATENT DOCUMENTS **Document Number** Date Country Code-Number-Kind Code MM-YYYY Country Name Classification Ν 0 Ρ Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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PTO-1449	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07977/252001	Application No. 09/198,073		PTO	
Information Disclosure Statement by Applicant		Applicant Shunpei Yamazaki, et al.			U.S. 11692	
(Use several she (37 CFR §1.98(b))	eets if necessary)	Filing Date November 23, 1998	Group Art Unit 2871	-	1011	

	U.S. Patent Documents							
Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate	
	AA	5,261,156	11/16/93	Mase et al.				
	AB	5,648,277	7/15/97	Zhang et al.				
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	Foreign Patent Documents or Published Foreign Patent Applications							
Examiner	Desig.	Document	Publication	Country or			Tran	slation
Initial	ID	Number	Date	Patent Office	Class	Subclass	Yes	No
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	AM	JP 10-135468	5/22/98	Japan			X	
	AN	JP 10-247735	9/14/98	Japan			X	
	AO	JP 07-135318	5/23/95	Japan			X	
	AP	JP 07-014880	1/17/95	Japan			Х	

	Other Documents (include Author, Title, Date, and Place of Publication)						
Examiner Initial	Desig. ID	Document					
	AQ						
	AR						
	AS						
	ΑT						

Examiner Signature	Date Considered				
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